

### IGBT<sup>3</sup> Chip

#### FEATURES:

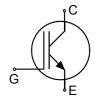
- 600V Trench & Field Stop technology
- low V<sub>CE(sat)</sub>
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

#### This chip is used for:

- power module
- discrete components

#### Applications:

- drives
- white goods
- resonant applications



Chip Type	V <sub>CE</sub>	I <sub>C</sub>	Die Size	Package
SIGC10T60E	600V	20A	3.19 x 3.21 mm <sup>2</sup>	sawn on foil

#### **Mechanical Parameters**

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Raster size	3.19 x 3.21		
Emitter pad size (incl. gate pad)	2.004 x 2.413	mm <sup>2</sup>	
Gate pad size	0.361 x 0.513	mm	
Area total	10.2		
Thickness	70	μm	
Wafer size	200	mm	
Max.possible chips per wafer	2693		
Passivation frontside	Photoimide		
Pad metal	3200 nm AlSiCu		
Backside metal	Ni Ag –system suitable for epoxy and soft solder die bonding		
Die bond	Electrically conductive glue or solder		
Wire bond	Al, <500µm		
Reject ink dot size	Ø 0.65mm ; max 1.2mm		
Recommended storage environment	Store in original container, in dry nitrogen, in dark environment, < 6 month at an ambient temperature of 23°C		



#### **Maximum Ratings**

Parameter	Symbol	Value	Unit		
Collector-Emitter voltage, <i>T</i> <sub>vj</sub> =25 °C	V <sub>CE</sub>	600	V		
DC collector current, limited by $T_{vj max}$	I <sub>C</sub>	1)	Α		
Pulsed collector current, $t_p$ limited by $T_{vj max}$	I <sub>c,puls</sub>	60	Α		
Gate emitter voltage	V <sub>GE</sub>	±20	V		
Junction temperature range	T <sub>vj</sub>	-40 +175	°C		
Operating junction temperature	T <sub>vj</sub>	-40+150	°C		
Short circuit data <sup>2)</sup> $V_{GE}$ = 15V, $V_{CC}$ = 360V, $T_{vj}$ = 150°C	t <sub>sc</sub>	6	μs		
Reverse bias safe operating area <sup>2</sup> (RBSOA)	/ <sub>C,max</sub>	$I_{\rm C,max}$ = 40A, $V_{\rm CE,max}$ = 600V $T_{\rm vj} \le 150^{\circ}{\rm C}$			

<sup>1)</sup> depending on thermal properties of assembly

<sup>2</sup>) not subject to production test - verified by design/characterization

# Static Characteristics (tested on wafer), T<sub>vj</sub> =25 °C

Parameter	Symbol	Conditions	Value			Unit
	e y moer	Conditions	min.	typ.	max.	
Collector-Emitter breakdown voltage	$V_{(BR)CES}$	V <sub>GE</sub> =0V , <i>I</i> <sub>C</sub> = 2 mA	600			
Collector-Emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, <i>I</i> <sub>C</sub> =20A	1.1	1.5	1.9	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =290 $\mu$ A , $V_{\rm GE}$ = $V_{\rm CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =600V , V <sub>GE</sub> =0V			1.1	μA
Gate-Emitter leakage current	I <sub>GES</sub>	V <sub>CE</sub> =0V , V <sub>GE</sub> =20V			300	nA
Integrated gate resistor	r <sub>G</sub>					Ω

Dynamic Characteristics (not subject to production test - verified by design / characterization),

*T*<sub>vj</sub> =25 °C

Parameter	Symbol	Conditions	Value			Unit
Faranieler	Symbol	Conditions	min.	typ.	max.	Unit
Input capacitance	Cies	V <sub>CE</sub> =25V,		1100		
Output capacitance	Coes	V <sub>GE</sub> =0V,		71		pF
Reverse transfer capacitance	Cres	<i>f</i> =1MHz		32		

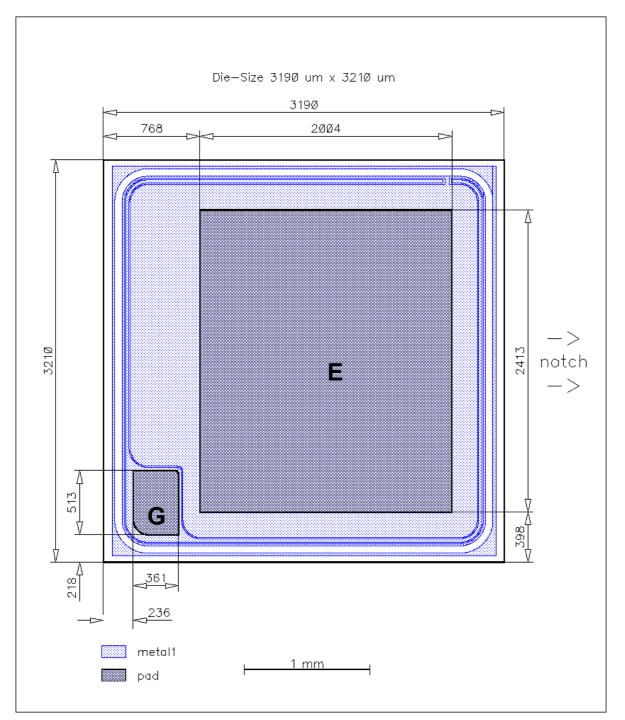


#### **Further Electrical Characteristic**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.



#### Chip Drawing





G = Gate



#### Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

#### **Revision History**

Version	Subjects (major changes since last revision)	Date
2.1	Wafer diameter change to 200 mm	06.07.2010

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